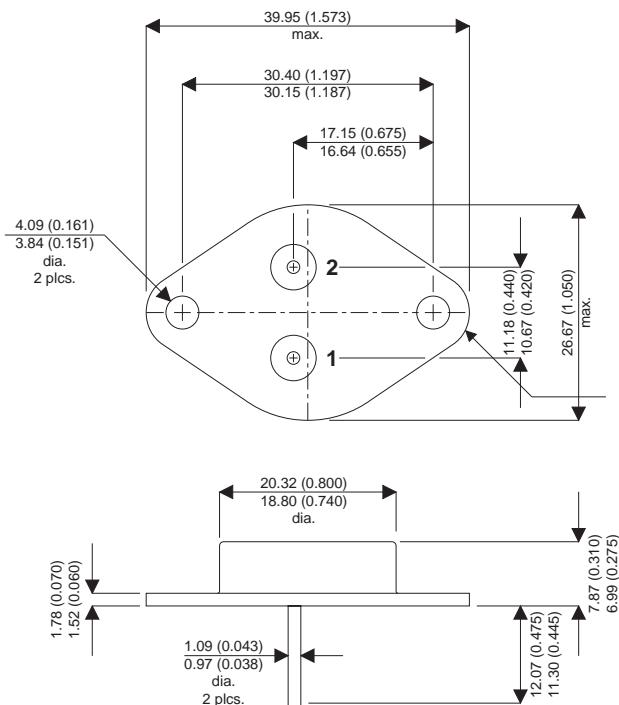


**SEME
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IRF9230

MECHANICAL DATA

Dimensions in mm (inches)



TO-3 Metal Package

Pin 1 – Gate

Pin 2 – Source

Case – Drain

P-CHANNEL POWER MOSFET

V_{DSS}	-200V
I_D(cont)	-6.5A
R_{DS(on)}	0.8Ω

FEATURES

- HERMETICALLY SEALED TO-3 METAL PACKAGE
- SIMPLE DRIVE REQUIREMENTS
- SCREENING OPTIONS AVAILABLE

ABSOLUTE MAXIMUM RATINGS ($T_{case} = 25^\circ\text{C}$ unless otherwise stated)

V_{GS}	Gate – Source Voltage	$\pm 20\text{V}$
I_D	Continuous Drain Current ($V_{GS} = 0, T_{case} = 25^\circ\text{C}$)	-6.5A
I_D	Continuous Drain Current ($V_{GS} = 0, T_{case} = 100^\circ\text{C}$)	-4A
I_{DM}	Pulsed Drain Current 1	-28A
P_D	Power Dissipation @ $T_{case} = 25^\circ\text{C}$	75W
	Linear Derating Factor	0.6W/ $^\circ\text{C}$
E_{AS}	Single Pulse Avalanche Energy 2	66mJ
I_{AR}	Avalanche Current 2	-6.5A
E_{AR}	Repetitive Avalanche Energy 2	7.5mJ
dv/dt	Peak Diode Recovery 3	-5V/ns
T_J, T_{stg}	Operating and Storage Temperature Range	-55 to +150°C
T_L	Lead Temperature 1.6mm (0.63") from case for 10 sec.	300°C

Notes

- 1) Pulse Test: Pulse Width $\leq 300\mu\text{s}$, $\delta \leq 2\%$
- 2) @ $V_{DD} = -50\text{V}$, $L \geq 2.3\text{mH}$, $R_G = 25\Omega$, Peak $I_L = -6.5\text{A}$, Starting $T_J = 25^\circ\text{C}$
- 3) @ $I_{SD} \leq -6.5\text{A}$, $di/dt \leq -100\text{A}/\mu\text{s}$, $V_{DD} \leq BV_{DSS}$, $T_J \leq 150^\circ\text{C}$, Suggested $R_G = 7.5\Omega$



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ELECTRICAL CHARACTERISTICS ($T_{case} = 25^\circ C$ unless otherwise stated)

Parameter	Test Conditions	Min.	Typ.	Max.	Unit
STATIC ELECTRICAL RATINGS					
BV_{DSS}	Drain – Source Breakdown Voltage $V_{GS} = 0$ $I_D = -1mA$	-200			V
ΔBV_{DSS}	Temperature Coefficient of Breakdown Voltage $I_D = -1mA$		-0.2		$V/^\circ C$
$R_{DS(on)}$	Static Drain – Source On-State Resistance 1 $V_{GS} = 10V$ $I_D = -4A$			0.80	Ω
	$V_{GS} = 10V$ $I_D = -6.5A$			0.92	
$V_{GS(th)}$	Gate Threshold Voltage $V_{DS} = V_{GS}$ $I_D = -250mA$	-2		-4	V
g_{fs}	Forward Transconductance ¹ $V_{DS} \geq -15V$ $I_{DS} = -4A$	2			S (Ω)
I_{DSS}	Zero Gate Voltage Drain Current $V_{GS} = 0$ $V_{DS} = 0.8BV_{DSS}$ $T_J = 125^\circ C$			-25	μA
I_{GSS}	Forward Gate – Source Leakage $V_{GS} = -20V$			-100	
I_{GSS}	Reverse Gate – Source Leakage $V_{GS} = 20V$			100	nA
DYNAMIC CHARACTERISTICS					
C_{iss}	Input Capacitance $V_{GS} = 0$		700		pF
C_{oss}	Output Capacitance $V_{DS} = -25V$		200		
C_{rss}	Reverse Transfer Capacitance $f = 1MHz$		40		
Q_g	Total Gate Charge $V_{GS} = -10V$	8		31	nC
Q_{gs}	Gate – Source Charge $I_D = -6.5A$	0.8		7.0	
Q_{gd}	Gate – Drain ("Miller") Charge $V_{DS} = 0.5BV_{DSS}$	5.0		17	
$t_{d(on)}$	Turn-On Delay Time			50	ns
t_r	Rise Time			100	
$t_{d(off)}$	Turn-Off Delay Time			100	
t_f	Fall Time			80	
SOURCE – DRAIN DIODE CHARACTERISTICS					
I_S	Continuous Source Current			-6.5	A
I_{SM}	Pulse Source Current ²			-28	
V_{SD}	Diode Forward Voltage ¹ $I_S = -6.5A$ $T_J = 25^\circ C$ $V_{GS} = 0$			-6.0	V
t_{rr}	Reverse Recovery Time ¹ $I_F = -6.5A$ $T_J = 25^\circ C$			400	ns
Q_{rr}	Reverse Recovery Charge $d_i / d_t \leq -100A/\mu s$ $V_{DD} \leq -50V$			4	μC
t_{on}	Forward Turn-On Time		Negligible		
PACKAGE CHARACTERISTICS					
L_D	Internal Drain Inductance (measured from 6mm down drain lead to centre of die)		5.0		nH
L_S	Internal Source Inductance (from 6mm down source lead to source bond pad)		13		
THERMAL CHARACTERISTICS					
$R_{\theta JC}$	Thermal Resistance Junction – Case			1.67	$^\circ C/W$
$R_{\theta CS}$	Thermal Resistance Case – Sink		0.12		
$R_{\theta JA}$	Thermal Resistance Junction – Ambient			30	

Notes

- 1) Pulse Test: Pulse Width $\leq 300ms$, $\delta \leq 2\%$
- 2) Repetitive Rating – Pulse width limited by maximum junction temperature.